

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	09265073	OVARD ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Nam V Nguyen	2612

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
340	10.4;	4/24/09	NN
455	38.2; 106; 73	4/24/09	NN

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Search EAST: uspat; us-pub; epo; jpo and derwent (updated search).	4/24/09	NN
Search Terms: interrogation with plurality of stations; rf circuitry for different ranges.	4/24/09	NN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
SAME AS	ABOVE	4/24/09	NN

/N. V. N./  
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